Model Question Paper

BVL515D

	USN 1 B I	
	Fifth Semester B.E Degree Examination	
	VLSI Fabrication Technology	
	Module -1	
1.	a. What are the fundamental steps involved in IC processing?	(10 Marks
	b. Explain in detail schematic representation of Uniform and selective layers in silicon?	(10 Marks)
	OR	
2.	a. Describe Miniaturization in VLSI Circuits.	(10 Marks)
	b. Explain in detail PMOS IC Technology Fabrication Process?	(10 Marks)
	Module -2	
3.	a. Describe crystal growth and different types of defects?	(10 Marks)
	b. With diagram explain CZochralski (CZ) technique.	(10 Marks)
	OR	
4.	a. Explain characteristics and Evaluation of crystals.b. Briefly discussion etching and polishing process.	(10 Marks) (10 Marks)
	Module - 3	
5.	a. Discuss in detail buried layers and Epitaxial defects	(10 Marks)
	b. Explain Microscopic growth process and advanced CVD process.	(10 Marks)
	OR	
6.	a. Derive the mathematical analysis for growth mechanism and kinetics in oxidation process.	(10 Marks)
	b. Explain in details growth techniques, Kinetics and thin oxide properties.	(10 Marks)
	Module - 4	
7.	a. Discuss the differences between photolithography and other lithography techniques.	(10 Marks)
	b. What are the advantages of electron lithography over optical lithography? OR	(10 Marks
8.	a. Derive the mathematical analysis for growth mechanism and kinetics in oxidation process.	(10 Marks)
	b. Explain in details growth techniques, Kinetics and thin oxide properties.	(10 Marks)
	Module - 5	
9.	a. What are the properties of silicon dioxide that make it suitable as a dielectric material?	(10 Marks)
	b. Briefly explain metallization problems for integrated circuits.	(10 Marks)
	OR	
10.	a. Discuss the advantages and limitations of plasma-enhanced deposition techniques.	(10 Marks)

b. With neat diagram explain process steps for # aligned gate, source and drain-silicide formation.(10Marks)